SCAS210A - MAY 1987 - REVISED APRIL 1996

, ,	NT PACKAGE
, 	7 <sub>24</sub> 10E
1Y2 <b>[</b> ]2	23 1 1A1 22 1 1A2
1Y4 <b>4</b>	21 1 1A3 20 1 1A4
GND [ 6 GND [ 7	19 V <sub>CC</sub>
GND [ 8 2Y1 [ 9	17 2A1 16 2A2
2Y2 [ 10 2Y3 [ 11 2Y4 [ 12	15 2A3 14 2A4 13 2OF
	1Y1

#### description

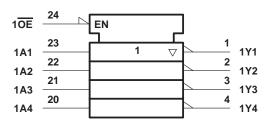
This octal buffer or line driver is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. This device provides inverting outputs and symmetrical active-low output-enable  $(\overline{OE})$  inputs. This device features high fan-out and improved fan-in.

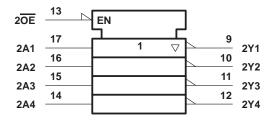
The 74ACT11240 is characterized for operation from -40°C to 85°C.

# FUNCTION TABLE (each buffer)

INP	UTS	OUTPUT
OE	Α	Υ
L	Н	L
L	L	Н
Н	X	Z

### logic symbol†





† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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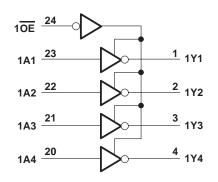
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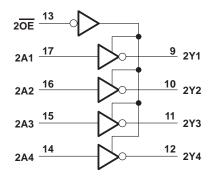


### 74ACT11240 OCTAL BUFFER/LINE DRIVER WITH 3-STATE OUTPUTS

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#### logic diagram (positive logic)





#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 6 V
Input voltage range, V <sub>I</sub> (see Note 1)	0.5 V to V <sub>CC</sub> + 0.5 V
Output voltage range, V <sub>O</sub> (see Note 1)	0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V <sub>CC</sub> or GND	±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2): DB pac	kage 0.65 W
DW pag	ckage 1.7 W
NT pac	kage 1.3 W
Storage temperature range, T <sub>stg</sub>	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
V <sub>IL</sub>	Low-level input voltage			0.8	V
VI	Input voltage	0		VCC	V
VO	Output voltage	0		VCC	V
loh	High-level output current			-24	mA
loL	Low-level output current			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	ns/V
TA	Operating free-air temperature	-40		85	°C



The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the NT package, which has a trace length of zero.

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	PARAMETER TEST CONDITIONS		Т,	Δ = 25°C	;			UNIT
PARAMETER			MIN	TYP	MAX	MIN	MAX	UNII
	Jan - 50 vA	4.5 V	4.4			4.4		
	I <sub>OH</sub> = -50 μA	5.5 V	5.4			5.4		
V <sub>OH</sub>	Jan - 24 mA	4.5 V	3.94			3.8		V
	$I_{OH} = -24 \text{ mA}$		4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	I	4.5 V			0.1		0.1	
	I <sub>OL</sub> = 50 μA	5.5 V			0.1		0.1	
V <sub>OL</sub>	1	4.5 V			0.36		0.44	V
	I <sub>OL</sub> = 24 mA	5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.5		±5	μΑ
Ι <sub>Ι</sub>	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μΑ
Δl <sub>CC</sub> ‡	One input at 3.4 V, Other inputs at GND or V <sub>CC</sub>	5.5 V			0.9		1	mA
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4				pF
Co	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		10				pF

Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted)

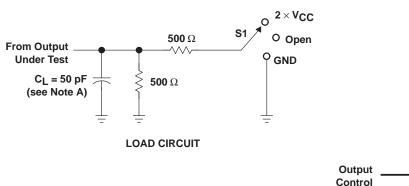
PARAMETER	FROM	то	T,	ղ = 25°C	;	MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	WAX	UNII
<sup>t</sup> PLH	A	V	1.5	6.5	9.9	1.5	10.6	ns
<sup>t</sup> PHL	A	1	1.5	6	8	1.5	8.7	115
<sup>t</sup> PZH	ŌĒ	V	1.5	7.5	11.7	1.5	12.5	ns
<sup>t</sup> PZL	OE	1	1.5	7.3	11.5	1.5	12.3	115
<sup>t</sup> PHZ	ŌĒ	V	1.5	7.3	9.4	1.5	10	nc
t <sub>PLZ</sub>	OE	'	1.5	7.9	10.3	1.5	10.8	ns

## operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

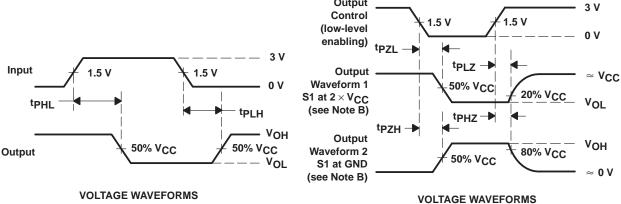
	PARAMETER		TEST CO	NDITIONS	TYP	UNIT
<u> </u>	Dower dissination canacitance per buffer	Outputs enabled	C 50 pE	f = 1 MHz	47	»E
Cpd	Power dissipation capacitance per buffer	Outputs disabled	$C_L = 50 \text{ pF},$	t = 1 MHz	13	p⊦

<sup>&</sup>lt;sup>‡</sup> This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V<sub>CC</sub>.

#### PARAMETER MEASUREMENT INFORMATION



TEST	<b>S</b> 1
tPLH/tPHL	Open
tPLZ/tPZL	2×V <sub>CC</sub>
tPHZ/tPZH	GND



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_Q = 50~\Omega$ ,  $t_f = 3$  ns,  $t_f = 3$  ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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